

Notice of References Cited

Application/Control No.

10/799,671

Applicant(s)/Patent Under
Reexamination
MUTIKAINEN ET AL.

Examiner

BEN H. LIU

Art Unit

2464

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,480,474 B2	11-2002	Johnson et al.	370/260
*	B	US-6,535,730 B1	03-2003	Chow et al.	455/416
*	C	US-2003/0108000 A1	06-2003	Chaney et al.	370/260
*	D	US-6,731,609 B1	05-2004	Hirni et al.	370/260
*	E	US-2004/0125933 A1	07-2004	Jun et al.	379/202.01
*	F	US-2004/0125932 A1	07-2004	Orbach et al.	379/202.01
*	G	US-6,775,269 B1	08-2004	Kaczmarczyk et al.	370/352
*	H	US-7,065,199 B1	06-2006	Hyllander et al.	379/211.02
*	I	US-7,155,528 B2	12-2006	Tam, Terry	709/230
*	J	US-7,184,415 B2	02-2007	Chaney et al.	370/260
*	K	US-7,233,589 B2	06-2007	Tanigawa et al.	370/352
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	X					

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